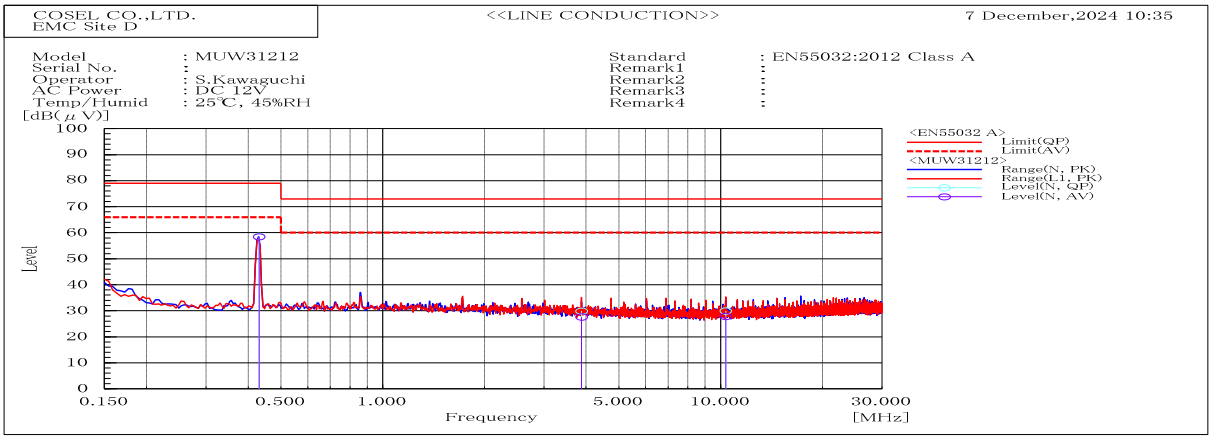
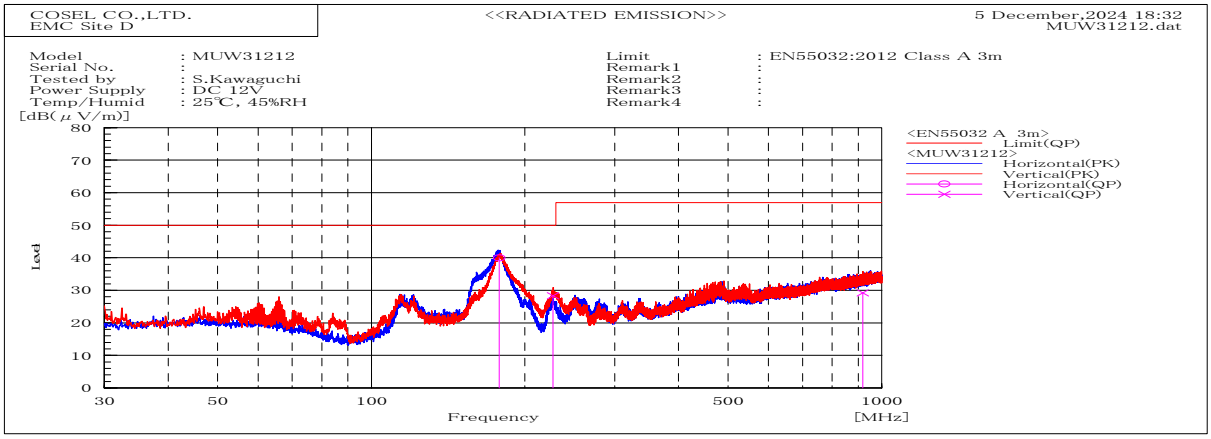
COSEL

DATA SHEET		Date	07-Dec-24
Model	MUW31212	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.431	N	58.6	58.4	79	66	20.4	7.6	Pass	
10.348	N	29.9	27.8	73	60	43.1	32.2	Pass	
3.88	N	29.8	27.6	73	60	43.2	32.4	Pass	

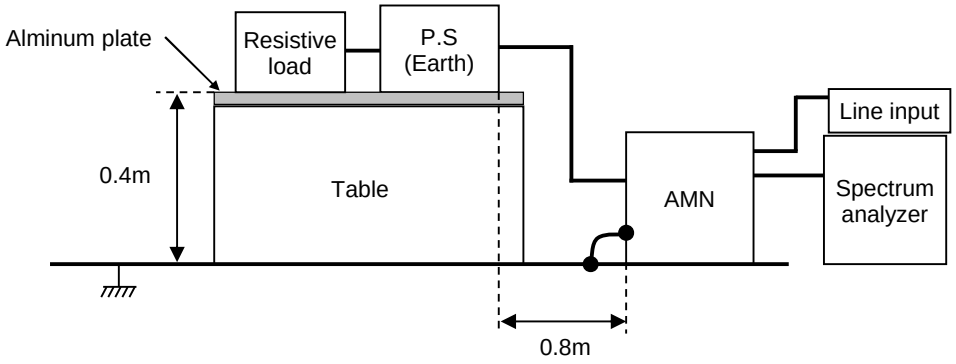


Frequency MHz	Polarization	Stability	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
177.984	H	Stable	40	50	10	Pass	199.7	228	
226.904	V	Stable	28.3	50	21.7	Pass	100.2	236.7	
917.842	V	Stable	29.2	57	27.8	Pass	144.7	69.5	

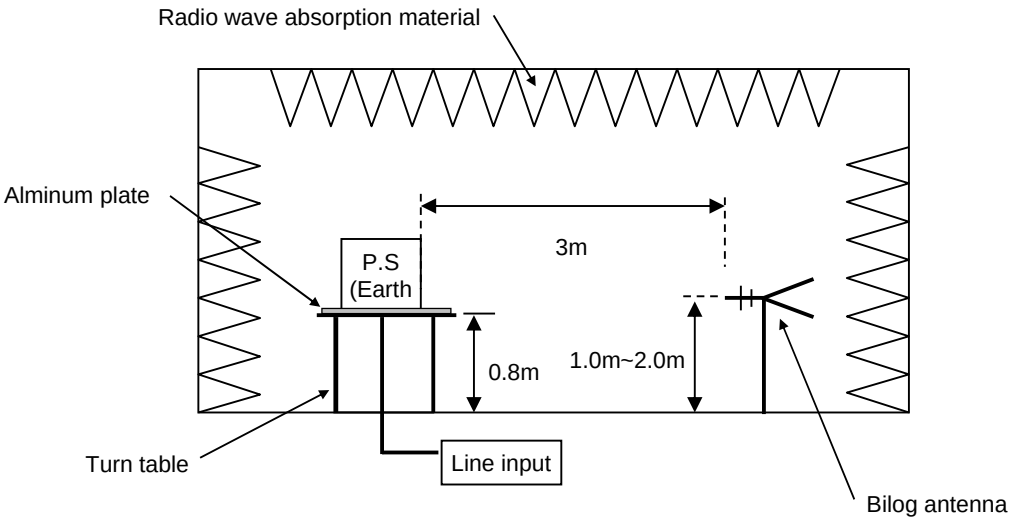
COSEL

DATA SHEET		Date	07-Dec-24
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission

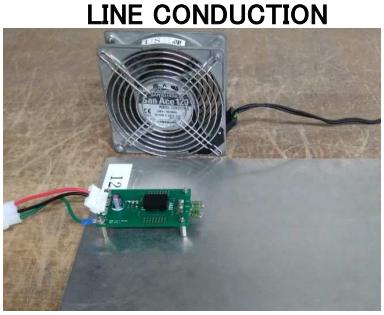


Conditions

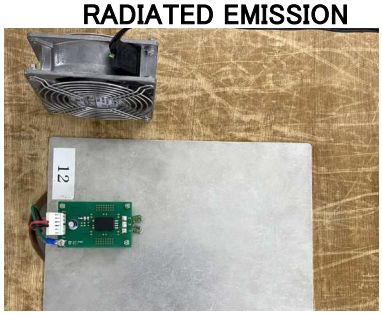
Test : EMI
Model Name: MUW3☐☐

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

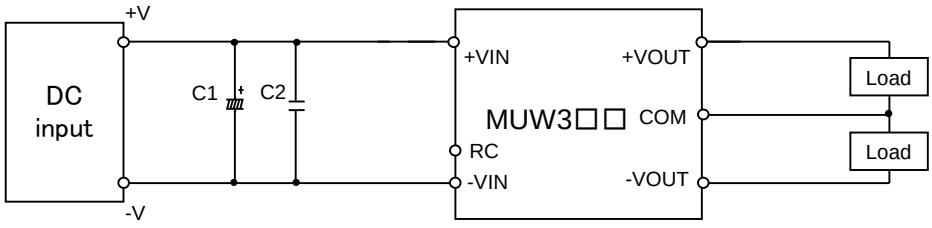


Fig.1 MUW305☐, MUW312☐, MUW324☐ Testing circuitry

C1 : MUW305☐ 16V 220μF Electric capacitor (UPWseries NICHICON)
MUW312☐ 50V 100μF Electric capacitor (UPWseries NICHICON)
MUW324☐ –

C2 : MUW305☐ 16V 22μF Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
MUW312☐ 25V 22μF Ceramic capacitor (C3216JB1E226MT TDK)
MUW324☐ 50V 10μF Ceramic capacitor (C3216X7R1H106KT TDK)

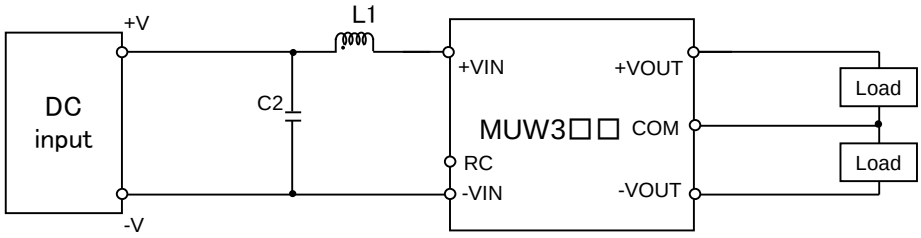


Fig.2 MUW348☐ Testing circuitry

C2 : MUW348☐ 100V 2.2μF Ceramic capacitor (C3216X7S2A225KT TDK)

L1 : MUW348☐ 520mA 15μH Inductor(LQH32PN150MN0L MURATA MANUFACTURING)